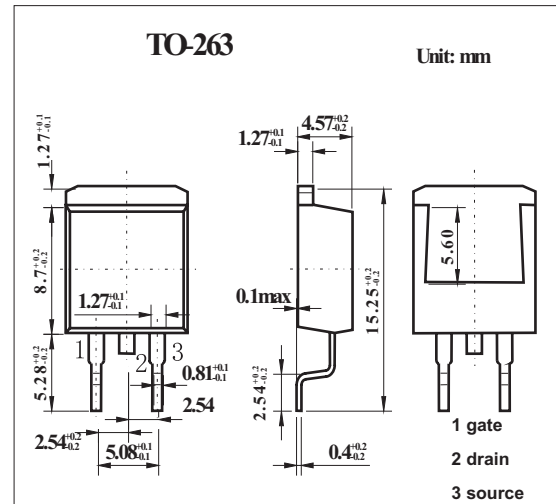
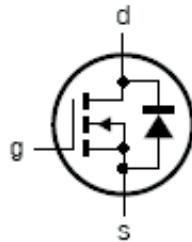


## TrenchMOS™ standard level FET

### KUK7604-40A

#### ■ Features

- TrenchMOS™ technology
- Q101 compliant
- 175°C rated
- Standard level compatible.



#### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
drain-source voltage (DC)	$V_{DS}$	40	V
drain-gate voltage (DC) $R_{GS} = 20\text{ k}\Omega$	$V_{DGR}$	40	V
gate-source voltage (DC)	$V_{GS}$	$\pm 20$	V
drain current (DC) $T_{mb} = 25^\circ\text{C}$ ; $V_{GS} = 10\text{ V}$	$I_D$	198	A
drain current (DC) $T_{mb} = 100^\circ\text{C}$ ; $V_{GS} = 10\text{ V}$		75	A
peak drain current *1	$I_{DM}$	794	A
total power dissipation $T_{mb} = 25^\circ\text{C}$	$P_{tot}$	300	W
storage temperature	$T_{stg}$	-55 to 175	$^\circ\text{C}$
operating junction temperature	$T_j$	-55 to 175	$^\circ\text{C}$
reverse drain current (DC) $T_{mb} = 25^\circ\text{C}$	$I_{DR}$	198	A
		75	A
pulsed reverse drain current *2	$I_{DRM}$	794	A
non-repetitive avalanche energy	$W_{DSS}$	1.6	J
thermal resistance from junction to ambient	$R_{th(j-a)}$	50	K/W
thermal resistance from junction to mounting base	$R_{th(j-mb)}$	0.5	K/W

\*1  $T_{mb} = 25^\circ\text{C}$ ; pulsed;  $t_p \leq 10\text{ }\mu\text{s}$ ;

\*2 unclamped inductive load;  $I_D = 75\text{ A}$ ;  $V_{DS} \leq 40\text{ V}$ ;  $V_{GS} = 10\text{ V}$ ;  $R_{GS} = 50\Omega$ , starting  $T_{mb} = 25^\circ\text{C}$

## KUK7604-40A

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
drain-source breakdown voltage	V <sub>(BR)DSS</sub>	I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 25°C	40			V
		I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>J</sub> = -55°C	36			V
gate-source threshold voltage	V <sub>GS(th)</sub>	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = 25°C	2	3	4	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = 175°C	1			V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = -55°C			4.4	V
drain-source leakage current	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 25°C		0.05	10	mA
		V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 175°C			500	mA
gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V; V <sub>DS</sub> = 0 V		2	100	nA
drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>J</sub> = 25°C		3.9	4.5	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>J</sub> = 175°C			8.5	mΩ
total gate charge	Q <sub>g(tot)</sub>			117		nC
gate-to-source charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V; V <sub>DD</sub> = 32 V; I <sub>D</sub> = 25 A		19		nC
gate-to-drain (Miller) charge	Q <sub>gd</sub>			50		nC
input capacitance	C <sub>iss</sub>			4300	5730	pF
output capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz		1400	1680	pF
reverse transfer capacitance	C <sub>rss</sub>			800	1100	pF
turn-on delay time	t <sub>d(on)</sub>			33		ns
rise time	t <sub>r</sub>			110		ns
turn-off delay time	t <sub>d(off)</sub>	V <sub>DD</sub> = 30 V; R <sub>L</sub> = 1.2Ω; V <sub>GS</sub> = 10 V; R <sub>G</sub> = 10Ω		151		ns
fall time	t <sub>f</sub>			76		ns
internal drain inductance	L <sub>d</sub>	from drain lead 6 mm from package to centre of die		4.5		nH
				2.5		nH
internal source inductance	L <sub>s</sub>	from source lead to source bond pad		7.5		nH
source-drain (diode forward) voltage	V <sub>SD</sub>	I <sub>S</sub> = 40 A; V <sub>GS</sub> = 0 V;		0.85	1.2	V
reverse recovery time	t <sub>rr</sub>	I <sub>S</sub> = 20 A; di <sub>S</sub> /dt = -100 A/μs		96		ns
recovered charge	Q <sub>r</sub>	V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 30 V		224		nC